

<b>Notice of References Cited</b>	Application/Control No. 10/021,504	Applicant(s)/Patent Under Reexamination FUJII, TETSUYA	
	Examiner Van Kim T. Nguyen	Art Unit 2151	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,622,179	09-2003	Welder, W. Dean	710/15
	B	US-6,578,142	06-2003	Anderson et al.	713/2
	C	US-6,513,113	01-2003	Kobayashi, Kazunori	713/2
	D	US-6,330,597	12-2001	Collin et al.	709/220
	E	US-6,263,387	07-2001	Chrabaszc, Michael	710/302
	F	US-6,175,868	01-2001	Lavian et al.	709/223
	G	US-5,764,593	06-1998	Turpin et al.	713/2
	H	US-5,530,895	06-1996	Enstrom, Mark R.	710/9
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.